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ATTORNEY DOCKET NO. CONFIRMATION NO. APPLICATION NO. FILING DATE FIRST NAMED INVENTOR 006601P086 7571 09/12/2003 Cassandra M Owen 10/660,646 **EXAMINER** 7590 10/05/2004 8791 FULLER, RODNEY EVAN BLAKELY SOKOLOFF TAYLOR & ZAFMAN 12400 WILSHIRE BOULEVARD ART UNIT PAPER NUMBER SEVENTH FLOOR LOS ANGELES, CA 90025-1030 2851

DATE MAILED: 10/05/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)		
Office Action Summary		10/660,646	OWEN ET AL.		
		Examiner	1	Art Unit	
		Rodney E Fuller	2851	AN	
	The MAILING DATE of this communicate			Iress	
Period for	Reply				
THE M - Extens after S - If the p - If NO p - Failure Any re	PRTENED STATUTORY PERIOD FOR IAILING DATE OF THIS COMMUNICATIONS of time may be available under the provisions of 37 MX (6) MONTHS from the mailing date of this communications of for reply specified above is less than thirty (30) dated for reply is specified above, the maximum statutor to reply within the set or extended period for reply will, the ply received by the Office later than three months after the patent term adjustment. See 37 CFR 1.704(b).	TION. CFR 1.136(a). In no event, however, may stion. ys, a reply within the statutory minimum of the property of the propert	a reply be timely filed nirty (30) days will be considered timely. DNTHS from the mailing date of this cor ABANDONED (35 U.S.C. § 133).		
Status					
1) 🛛 1	Responsive to communication(s) filed or	n <u>12 September 2003</u> .			
2a)□ -	This action is FINAL . 2b)	☐ This action is non-final.			
-	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.				
Dispositio	on of Claims				
4) \(\times \) (4) \(\times \) (5) \(\times \) (6) \(\times \) (7) \(\times \) (7	 Claim(s) 1-24 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. Claim(s) is/are allowed. Claim(s) 1-24 is/are rejected. 				
Application	on Papers				
10)⊠ T	The specification is objected to by the Extra control of the drawing(s) filed on 12 September 20 Applicant may not request that any objection Replacement drawing sheet(s) including the The oath or declaration is objected to by	203 is/are: a)⊠ accepted or by to the drawing(s) be held in abey correction is required if the drawing	ance. See 37 CFR 1.85(a). ng(s) is objected to. See 37 CFI	R 1.121(d).	
Priority u	nder 35 U.S.C. § 119				
a)[Acknowledgment is made of a claim for the cl	uments have been received. uments have been received in ne priority documents have bee Bureau (PCT Rule 17.2(a)).	Application No en received in this National S		
. 26	ee the attached detailed Office action fo	r a list of the certified copies no	Primary	ey Fuller Examiner	
Attachment(s)		4.5	to	
2) Notice 3) Inform	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-9 ation Disclosure Statement(s) (PTO-1449 or PTO No(s)/Mail Date	Paper N	v Summary (PTO-413) b(s)/Mail Date f Informal Patent Application (PTO-	.152)	

DETAILED ACTION

Specification

1. The spacing of the lines of the specification is such as to make reading and entry of amendments difficult. New application papers with lines double spaced on good quality paper are required.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1-24 are rejected under 35 U.S.C. 102(b) as being anticipated by Whiting (US 6,377,334).

Regarding claims 1, 9, 15 and 20, Whiting discloses "a multi-zone thermal sensing unit (Fig. 1, ref.# 22) containing a plurality of thermal sensor elements (column 4, lines 17-18) that detect the temperature of a plurality of pre-defined zones (column 3, line 67) on said substrates (Fig. 1, ref.# 20); a multi-zone thermal adjustment unit (Fig. 1, ref.# 10) containing a plurality of thermal coupler elements that adjusts the temperature of said pre-defined zones (column 3, line 67); and a thermal controller unit (Fig. 1, ref.# 12) operatively and communicatively coupled to said multi-zone thermal sensing unit and said multi-zone thermal adjustment unit (Fig. 1, lines connecting ref.#s 10, 12, 24), said thermal controller unit containing logic circuitry (Fig. 2, ref.# 40) to receive information from said multi-zone thermal sensing unit and said multi-zone thermal

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adjustment unit, to process information, and to supply information to said multi-zone thermal sensing unit and said multi-zone thermal adjustment unit, wherein said multi-zone thermal sensing unit communicates detected temperature information to said thermal controller unit, and wherein said thermal controller unit processes said detected temperature information, generates temperature control information based on said processed temperature information (column 2, lines 30-38), and communicates said temperature control information to said multi-zone thermal adjustment unit to adjust the temperatures of said pre-defined zones (column 2, lines 60-67)."

Regarding claims 2, 7, 10, 13, 16 and 21, Whiting discloses "including an electronic storage device containing expected temperature information for said pre-defined zones." (column 5, lines 2-4)

Regarding claims 3, 16 and 21, Whiting discloses "wherein said thermal controller unit processes said detected temperature information by including comparisons between said detected temperature information and said expected temperature information stored in said electronic storage device." (column 5, lines 2-4)

Regarding claims 4, 7 and 13, Whiting discloses "wherein said thermal controller unit generates said temperature control information to adjust the temperatures of said pre-defined zones by determining whether said comparisons between said detected temperature information and said expected temperature information exceed a pre-specified threshold value." (column 5, lines 60-64)

Regarding claims 5 8, 11 and 14, Whiting discloses "a measurement processing module (Fig. 1, ref.# 22, 24, 26, 28) configured to measure attributes of said substrates and generate substrate attribute information." (column 4, lines 17-23)

Regarding claims 6, 8, 12, 14, 17 and 22, Whiting discloses "revising said expected temperature information for said pre-defined zones based on said substrate attribute information." (column 5, lines 61-64)

Regarding claim 15, Whiting discloses "a lithographic apparatus including, an illuminator to provide a projection beam of radiation, a support to hold a patterning device, the patterning device configured to pattern the projection beam according to a desired pattern, a substrate table configured to hold a substrate, and a projection system to expose the patterned beam onto a target portion of the substrate." (column 2, line 29) (Note: All typical lithographic systems include an illuminator, a support, a reticle, a substrate table and a projection system.)

Regarding claims 18 and 23, Whiting discloses "wherein said at least one processing module is configured as a developer module to develop said wafer, said developer module including an application nozzle to uniformly distribute a solution." (column 2, line 30)

Regarding claims 19 and 24, Whiting discloses "wherein said wafer track apparatus further includes a rinse module dedicated to rinsing said developed substrate, said rinse module including a cleaning nozzle to distribute a cleaning solution, a spinning plate that receives said developed substrate, and a holding device to firmly attach said developed substrate to said spinning plate." (column 2, lines 26-30)

Regarding claim 20, Whiting discloses "a measurement processing module (Fig. 1, ref. # 22, 24, 26, 28) to measure attributes of a substrate and generate substrate attribute information at least one processing module configured to chemically process said substrate." (column 4, lines 17-23)

Art Unit: 2851

Conclusion

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Rodney E Fuller whose telephone number is 571-272-2118. The examiner can normally be reached on 8:00am - 4:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Judy Nguyen can be reached on 571-272-2258. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Rodney E Fuller Primary Examiner Art Unit 2851

September 29, 2004